

**Search Notes**

Application/Control No.

09/628,108

Examiner

Christopher A. Revak

Applicant(s)/Patent under  
Reexamination

FUJIYAMA ET AL.

Art Unit

2131

**SEARCHED**

Class	Subclass	Date	Examiner
713	200,201	5/11/2005	CR
709	223,224	5/11/2005	CR
705	400	5/11/2005	CR
707	1,3,6	5/11/2005	CR
707	100,102	5/11/2005	CR
707	200,203	5/11/2005	CR
715	700	5/11/2005	CR
715	733-736	5/11/2005	CR
717	168-178	5/11/2005	CR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
713	200,201	5/11/2005	CR
705	400	5/11/2005	CR
715	733-736	5/11/2005	CR
707/1,3,6,100,102,200, 203		5/11/2005	CR

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM Inventor Name Search	5/11/2005	CR
BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PG PUB, USOCR	5/11/2005	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	5/11/2005	CR